


Search Notes 	Application/Control No. 10644445	Applicant(s)/Patent Under Reexamination ANDERSON ET AL.
	Examiner Chawan, Sheela C	Art Unit 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	187, 174,177, 203,289,	1/29/07	SCC
709	217-219,229-232,211-212,247	"	"
711	161-162	"	"
216	24,33,41,52	"	"
725	135,138,32, 90	"	"
715	758	"	"
ABOVE SEARCH UP- DATE.		3/31/07	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US-PGPUB,USPAT, EPO., JPO, DERWENT,IBM-TDB.	1/29/07	SCC
INVENTOR NAME SEARCH.	"	"
SEARCH EAST, AND OTHER DATABASE SEE THE ATTACHED SEARCH HISTORY.	3/31/07	SCC
382/187,177.CCLS.US-PATENT ONLY SEE TEXT SEARCH.	3/31/07	SCC
709/212,231,247.CCLS. "	3/31/07	SCC
INTERFERENCE SEARCH , SEE SEARCH HISTORY PRINT OUT.	3/31/07	SCC
SEARCH IEEE OR INSPEC DATABASE.	3/31/07	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	187	3/31/07	SCC
709	212,231,247	3/31/07	SCC